## N-channel $600 \mathrm{~V}, 0.71 \Omega$ typ., 5.5 A MDmesh ${ }^{\text {TM }}$ M2 Power MOSFET in a TO-220FP package

Datasheet - production data


Figure 1: Internal schematic diagram


Features

| Order code | V $_{\text {DS }}$ | $\mathbf{R}_{\text {DS(on) }}$ max. | $\mathbf{I}_{\mathbf{D}}$ |
| :---: | :---: | :---: | :---: |
| STF9HN65M2 | 600 V | $0.82 \Omega$ | 5.5 A |

- Extremely low gate charge
- Excellent output capacitance ( $\mathrm{C}_{\text {oss }}$ ) profile
- $100 \%$ avalanche tested
- Zener-protected


## Applications

- Switching applications


## Description

This device is an N-channel Power MOSFET developed using MDmesh ${ }^{\text {M }}$ M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

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## 1 Electrical ratings

Table 2: Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
| :---: | :---: | :---: | :---: |
| $V_{G S}$ | Gate-source voltage | $\pm 25$ | V |
| $\mathrm{I}^{(1)}$ | Drain current (continuous) at $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ | 5.5 | A |
| $\mathrm{I}^{(1)}$ | Drain current (continuous) at $\mathrm{T}_{\mathrm{C}}=10{ }^{\circ} \mathrm{C}$ | 3.5 | A |
| $\mathrm{IDM}^{(2)}$ | Drain current (pulsed) | 22 | A |
| $\mathrm{P}_{\text {TOT }}$ | Total dissipation at $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ | 20 | W |
| $\mathrm{dv} / \mathrm{dt}{ }^{(3)}$ | Peak diode recovery voltage slope | 15 | V/ns |
| $\mathrm{dv} / \mathrm{dt}{ }^{(4)}$ | MOSFET dv/dt ruggedness | 50 | V/ns |
| Viso | Insulation withstand voltage (RMS) from all three leads to external heat sink $\left(\mathrm{t}=1 \mathrm{~s}, \mathrm{~T}_{\mathrm{C}}=25^{\circ} \mathrm{C}\right)$ | 2500 | VIso |
| $\mathrm{T}_{\text {stg }}$ | Storage temperature | - 55 to 150 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\mathrm{j}}$ | Max. operating junction temperature | 150 |  |

## Notes

${ }^{(1)}$ Limited only by maximum temperature allowed.
${ }^{(2)}$ Pulse width limited by safe operating area.
${ }^{(3)}$ ISD $\leq 5.5 \mathrm{~A}$, di/dt $\leq 400 \mathrm{~A} / \mu \mathrm{s} ; \mathrm{V}_{\text {DS peak }}<\mathrm{V}_{\text {(BR) }}$ DSS, $\mathrm{V}_{\mathrm{DD}}=80 \% \mathrm{~V}_{\text {(BR)DSS }}$
${ }^{(4)} \mathrm{V}_{\mathrm{DS}} \leq 520 \mathrm{~V}$.

Table 3: Thermal data

| Symbol | Parameter | Value | Unit |
| :---: | :--- | :---: | :---: |
| $\mathrm{R}_{\mathrm{th} \text {-case }}$ | Thermal resistance junction-case max. | 6.25 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| $\mathrm{R}_{\mathrm{th} j \text {-amb }}$ | Thermal resistance junction-ambient max. | 62.5 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |

Table 4: Avalanche characteristics

| Symbol | Parameter | Value | Unit |
| :---: | :--- | :---: | :---: |
| $\mathrm{I}_{\mathrm{AR}}$ | Avalanche current, repetetive or not repetetive <br> (pulse width limited by $\left.\mathrm{T}_{\mathrm{jmax}}\right)$ | 1.0 | A |
| $\mathrm{E}_{\mathrm{AS}}$ | Single pulse avalanche energy (starting $\mathrm{T}_{\mathrm{j}}=25^{\circ} \mathrm{C}$, <br> $\mathrm{I}_{\mathrm{D}}=\mathrm{I}_{\mathrm{AR}}, V_{D D}=50 \mathrm{~V}$ ) | 105 | mJ |

## 2 Electrical characteristics

( $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ unless otherwise specified).
Table 5: Static

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $V_{\text {(BR) }}$ DSS | Drain-source breakdown voltage | $\mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=1 \mathrm{~mA}$ | 650 |  |  | V |
| Idss | Zero gate voltage drain current | $\mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{~V}_{\mathrm{DS}}=650 \mathrm{~V}$ |  |  | 1 | $\mu \mathrm{A}$ |
|  |  | $\begin{aligned} & \mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{~V}_{\mathrm{DS}}=650 \mathrm{~V}, \\ & \mathrm{~T}_{\mathrm{C}}=125^{\circ} \mathrm{C} \end{aligned}$ |  |  | 100 | $\mu \mathrm{A}$ |
| Igss | Gate-body leakage current | $\mathrm{V}_{\mathrm{DS}}=0 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}= \pm 25 \mathrm{~V}$ |  |  | $\pm 10$ | $\mu \mathrm{A}$ |
| $\mathrm{V}_{\mathrm{GS}(\mathrm{th})}$ | Gate threshold voltage | $\mathrm{V}_{\mathrm{DS}}=\mathrm{V}_{\mathrm{GS}}, \mathrm{I}_{\mathrm{D}}=250 \mu \mathrm{~A}$ | 2 | 3 | 4 | V |
| $\mathrm{R}_{\mathrm{DS} \text { (on) }}$ | Static drain-source onresistance | $\mathrm{V}_{G S}=10 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=2.5 \mathrm{~A}$ |  | 0.71 | 0.82 | $\Omega$ |

Table 6: Dynamic

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{C}_{\text {iss }}$ | Input capacitance | $\mathrm{V}_{\mathrm{DS}}=100 \mathrm{~V}, \mathrm{f}=1 \mathrm{MHz}, \mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}$ | - | 325 | - | pF |
| Coss | Output capacitance |  | - | 16 | - | pF |
| $\mathrm{Crss}^{\text {r }}$ | Reverse transfer capacitance |  | - | 0.85 | - | pF |
| Coss eq. ${ }^{(1)}$ | Equivalent output capacitance | $\mathrm{V}_{\mathrm{DS}}=0 \mathrm{~V}$ to $520 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=0 \mathrm{~V}$ | - | 109 | - | pF |
| $\mathrm{R}_{\mathrm{G}}$ | Intrinsic gate resistance | $\mathrm{f}=1 \mathrm{MHz}$ open drain | - | 5.6 | - | $\Omega$ |
| $\mathrm{Qg}_{9}$ | Total gate charge | $\mathrm{V}_{\mathrm{DD}}=520 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=5 \mathrm{~A}, \mathrm{~V}_{\mathrm{GS}}=10 \mathrm{~V}$ (see Figure 15: "Gate charge test circuit') | - | 11.5 | - | nC |
| $\mathrm{Qg}_{\mathrm{gs}}$ | Gate-source charge |  | - | 2.5 | - | nC |
| $\mathrm{Qg}_{\mathrm{gd}}$ | Gate-drain charge |  | - | 5 | - | nC |

## Notes:

${ }^{(1)} C_{o s s ~ e q . ~}^{\text {is }}$ defined as a constant equivalent capacitance giving the same charging time as $C_{\text {oss }}$ when $V_{D S}$ increases from 0 to 80\% VDSs.

Table 7: Switching times

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{t}_{\mathrm{d}(\mathrm{on})}$ | Turn-on delay time | $\mathrm{V}_{\mathrm{DD}}=325 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=2.5 \mathrm{~A} \mathrm{R}_{\mathrm{G}}=4.7 \Omega,$ <br> $\mathrm{V}_{\mathrm{GS}}=10 \mathrm{~V}$ (see Figure 14: <br> "Switching times test circuit for resistive load" and Figure 19: <br> "Switching time waveform") | - | 7.5 | - | ns |
| $\mathrm{t}_{\mathrm{r}}$ | Rise time |  | - | 4.6 | - | ns |
| $\mathrm{t}_{\mathrm{d} \text { (off) }}$ | Turn-off-delay time |  | - | 24 | - | ns |
| $\mathrm{t}_{\mathrm{f}}$ | Fall time |  | - | 14.5 | - | ns |

Table 8: Source-drain diode

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| ISD | Source-drain current |  | - |  | 5.5 | A |
| $\mathrm{ISDM}^{(1)}$ | Source-drain current (pulsed) |  | - |  | 22 | A |
| $\mathrm{V}_{\text {SD }}{ }^{(2)}$ | Forward on voltage | $\mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{I}_{\text {SD }}=5 \mathrm{~A}$ | - |  | 1.6 | V |
| $\mathrm{t}_{\mathrm{rr}}$ | Reverse recovery time | $\mathrm{I}_{\mathrm{sD}}=5 \mathrm{~A}, \mathrm{di} / \mathrm{dt}=100 \mathrm{~A} / \mu \mathrm{s},$ <br> $V_{D D}=60 \mathrm{~V}$ (see Figure 16: " Test circuit for inductive load switching and diode recovery times") | - | 268 |  | ns |
| Q ${ }_{\text {Ir }}$ | Reverse recovery charge |  | - | 1.7 |  | $\mu \mathrm{C}$ |
| IRRM | Reverse recovery current |  | - | 12.5 |  | A |
| $\mathrm{trrr}^{\text {r }}$ | Reverse recovery time | $\begin{aligned} & \mathrm{I}_{\mathrm{SD}}=5 \mathrm{~A}, \mathrm{di} / \mathrm{dt}=100 \mathrm{~A} / \mu \mathrm{s}, \\ & \mathrm{~V}_{\mathrm{DD}}=60 \mathrm{~V}, \mathrm{~T}_{\mathrm{j}}=150^{\circ} \mathrm{C} \end{aligned}$ <br> (see Figure 16: " Test circuit for inductive load switching and diode recovery times") | - | 408 |  | ns |
| Qrr | Reverse recovery charge |  | - | 2.6 |  | $\mu \mathrm{C}$ |
| $I_{\text {RRM }}$ | Reverse recovery current |  | - | 13 |  | A |

## Notes:

${ }^{(1)}$ Pulse width is limited by safe operating area.
${ }^{(2)}$ Pulse test: pulse duration $=300 \mu \mathrm{~s}$, duty cycle $1.5 \%$.

### 2.1 Electrical characteristics (curves)

Figure 2: Safe operating area


Figure 3: Thermal impedance


Figure 4: Output characteristics


Figure 5: Transfer characteristics


Figure 6: Normalized gate threshold voltage vs. temperature


Figure 7: Normalized $\mathrm{V}_{\text {(BR)Dss }}$ vs. temperature



Figure 10: Gate charge vs. gate-source voltage

Figure 11: Capacitance variations



Figure 12: Output capacitance stored energy


Figure 13: Source-drain diode forward characteristics


## 3 Test circuits



Figure 16: Test circuit for inductive load switching and diode recovery times


Figure 17: Unclamped inductive load test circuit


Figure 18: Unclamped inductive waveform


Figure 19: Switching time waveform


## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK ${ }^{\circledR}$ packages, depending on their level of environmental compliance. ECOPACK ${ }^{\circledR}$ specifications, grade definitions and product status are available at: www.st.com. ECOPACK ${ }^{\circledR}$ is an ST trademark.
4.1 TO-220FP package information

Figure 20: TO-220FP package outline


Table 9: TO-220FP mechanical data

| Dim. | mm |  |  |
| :---: | :---: | :---: | :---: |
|  | Min. | Typ. | Max. |
| A | 4.4 |  | 4.6 |
| B | 2.5 |  | 2.7 |
| D | 2.5 |  | 2.75 |
| E | 0.45 |  | 0.7 |
| F | 0.75 |  | 1 |
| F1 | 1.15 |  | 1.70 |
| F2 | 1.15 |  | 1.70 |
| G | 4.95 |  | 5.2 |
| G1 | 2.4 |  | 2.7 |
| H | 10 |  | 10.4 |
| L2 |  |  | 30.6 |
| L3 | 28.6 |  | 10.6 |
| L4 | 9.8 |  | 3.6 |
| L5 | 2.9 |  | 16.4 |
| L6 | 15.9 |  | 9.3 |
| L7 | 9 |  | 3.2 |
| Dia | 3 |  |  |

## 5 Revision history

Table 10: Document revision history

| Date | Revision | Changes |
| :---: | :---: | :--- |
| 11-Mar-2015 | 1 | Initial release. |
| 23-Apr-2015 | 2 | Document status promoted to 'Production data'. |

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